L Number	Hits	Search Text	DB	Time stamp
11	5	(semiconductor near (test or testing)) and ((digital adj tester) or (test adj (pattern or vector or stimuli))) and loop and (failure near2 rate)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/05/28 16:55
14	7	("4055801" | "4807161" | "4866714" | "4868785" | "5001714" | "5325309" | "5371851").PN.	USPAT	2002/05/28 17:13
15	9	5557559.URPN.	USPAT	2002/05/28 17:13
-	90	((702/35,57-59,64,65,69,72,75-80,108,117-128,134,182...).ccls.) and (semiconductor near2 (test or testing))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/05/21 15:20
-	45	((324/500,501,512,520-535,537,750-755,763,765...,555,...,702,703,705,...) and (semiconductor near2 (test or testing)) and (heat or heating) and (resistive or resistivity)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/05/21 10:51
-	38	((438/14-18).ccls.) and (semiconductor near2 (test or testing)) and (heat or heating or temperature or thermal or thermally) and (resistive or resistivity)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/05/21 10:52
-	30	((326/37-47,101).ccls.) and (semiconductor near2 (test or testing))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/05/21 10:52
-	18	((714/25,30,32,33,37,40,41,724-745).ccls.) and (semiconductor near2 (test or testing)) and (resistive or resistivity)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/05/21 10:52
-	106	(semiconductor near (test or testing)) and (laser or (optical adj microscope)) and (resistive or resistivity)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/05/22 04:22
-	69	(semiconductor near2 (test or testing)) and (state?change or state?changes or state?changing or (state adj (change or changes or changing)))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/05/21 10:55
-	25	(semiconductor near2 (test or testing)) and (state?change or state?changes or state?changing or (state adj (change or changes or changing))) and (fail or fails or failed or failing or failure)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/05/21 10:55
-	7	(semiconductor near2 (test or testing)) and (state?change or state?changes or state?changing or (state adj (change or changes or changing))) and (fail or fails or failed or failing or failure) and (recover or recovers or recovered or recovering or recovery)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/05/21 10:56
-	11	("3761695" | "3783254" | "3784907" | "3961251" | "3961252" | "4298980" | "4329460" | "4357703" | "4504784" | "4519078" | "4561095").PN.	USPAT	2002/05/21 10:56
-	19	4669081.URPN.	USPAT	2002/05/22 04:50
-	0	4669081.URPN. and (laser or microscope or resistive or resistivity)	USPAT	2002/05/21 10:58

-	6	(semiconductor near2 (test or testing)) and (burn?in or (burn adj in) or burnin) and ((resistive or resistivity) near3 (test or testing))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/05/21 10:58
-	11	(semiconductor near2 (test or testing)) and (burn?in or (burn adj in) or burnin) and ((laser or optical) near2 (scan or scanning))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/05/21 10:59
-	119	edward near2 cole	USPAT	2002/05/21 11:00
-	1	"4698587".PN.	USPAT	2002/05/21 11:00
-	14	5430305.URPN.	USPAT	2002/05/21 11:00
-	4	("5422498" | "5430305" | "5708371" | "5844416").PN.	USPAT	2002/05/21 11:00
-	4	6078183.URPN.	USPAT	2002/05/21 11:01
-	688	semiconductor and ((digital adj tester) or (test adj pattern)) and loop	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/05/22 06:25
-	566	semiconductor and ((digital adj tester) or (test adj pattern)) and loop and (error or fail or failure or fault)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/05/22 08:37
-	8	semiconductor and ((digital adj tester)) and loop and (error or fail or failure or fault)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/05/28 11:50
-	0	semiconductor and ((digital adj tester)) and (loop or cycle) and ((error or fail or failure or fault) near2 (inject or injection))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/05/22 08:41
-	0	semiconductor and ((digital adj tester)) and (rate) and ((error or fail or failure or fault) near2 (inject or injection))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/05/22 08:42
-	0	resistive near interconnection near localization	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/05/28 11:55
-	18	("3840861" | "3881173" | "4538265" | "4633434" | "4669081" | "4670876" | "4759019" | "4779271" | "4794517" | "4835459" | "4999837" | "5008885" | "5321698" | "5495590" | "5564014" | "5671352" | "5687338" | "5701409").PN.	USPAT	2002/05/28 10:01
-	12	semiconductor and ((digital adj tester)) and (loop or (failure adj rate))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/05/28 11:54
-	8	(semiconductor near (test or testing)) and (heat or heating) and laser and ((thin or thinning) near3 die)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/05/28 12:00
-	2	(semiconductor near (test and testing)) and loop and (failure near rate)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/05/28 16:20